



WANSEMI
万芯半导体

WP4614

Enhancement Mode N+P-Channel Power MOSFET

SOP8/N+PMOS/40V/ $\pm 20V$ /1.5V/8A/15m Ω

-40V/ $\pm 20V$ /-1.5V/-7A/33m Ω

Rev0.4

40V N+P-Channel MOSFET

1.Features

- ◆ High power and current handling capability
- ◆ Lead free product is acquired
- ◆ Fast switching
- ◆ Surface mount package

◆ N-Channel

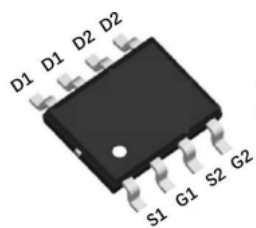
V_{DS}	$R_{DS(on)}$ Typ.	I_D
40V	15mΩ @ 10V	8A
	20mΩ @ 4.5V	

◆ P-Channel

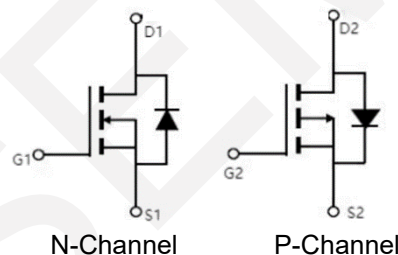
V_{DS}	$R_{DS(on)}$ Typ.	I_D
-40V	33mΩ @ -10V	-7A
	42mΩ @ -4.5V	

2.Applications

- ◆ Power Switching Application
- ◆ Load Switching



SOP8
Pin Description



Schematic Diagram

3.Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.
WP4614	4614	SOP8	4,000	48,000

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	N-channel	P-channel	Units
Drain to Source Voltage	V_{DSS}	40	-40	V
Gate to Source Voltage	V_{GSS}	±20	±20	V
Drain Current (DC),	TA=25 °C	I_D	8	A
	TA=100 °C	I_D	5.2	A
Drain Current (Pulse), PW≤300μs	I_{DM}	40	-30	A
Total Dissipation	P_D	2.0	2.0	W
Junction Temperature	T_j	150	150	°C
Storage Temperature	T_{stg}	-55 to +150	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

5. Thermal Resistance Ratings (Note 2)

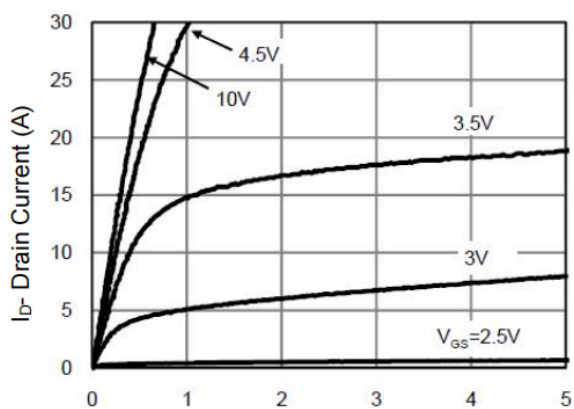
Parameter	Symbol	Value	Unit
Maximum Junction-to-Ambient	$R_{\theta JA}$	62.5	$^{\circ}\text{C/W}$

Note 2: When mounted on 1 inch square copper board $t \leq 10\text{sec}$ The value in any given application depends on the user's specific board design.

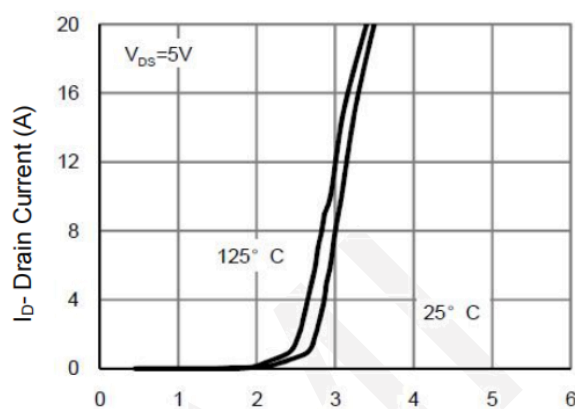
6. NMOS Electrical Characteristics at $T_a=25^{\circ}\text{C}$ (Note 3)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$I_D = 250\mu\text{A}$, $V_{GS} = 0\text{V}$	40			V
Zero-Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 40\text{V}$, $V_{GS} = 0\text{V}$			1	μA
Gate to Source Leakage Current	I_{GSS}	$V_{GS} = \pm 20\text{V}$, $V_{DS} = 0\text{V}$			± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_{DS}=250\mu\text{A}$	1.0	1.5	2.5	V
Static Drain to Source On-State Resistance	$R_{DS(on)}$	$I_D = 8\text{A}$, $V_{GS} = 10\text{V}$		15	20	$\text{m}\Omega$
		$I_D = 4\text{A}$, $V_{GS} = 4.5\text{V}$		20	30	$\text{m}\Omega$
Input Capacitance	C_{iss}	$V_{GS}=0\text{V}$, $V_{DS}=20\text{V}$, Frequency=1.0MHz		1110	-	pF
Output Capacitance	C_{oss}			114	-	pF
Reverse Transfer Capacitance	C_{rss}			109	-	pF
Turn-ON Delay Time	$t_{d(on)}$	$V_{DD} = 20\text{V}$ $V_{GS} = 10\text{V}$ $R_{GEN} = 2.5\Omega$ $I_D = 8\text{A}$		5.5	-	ns
Rise Time	t_r			14	-	ns
Turn-OFF Delay Time	$t_{d(off)}$			24	-	ns
Fall Time	t_f			12	-	ns
Total Gate Charge	Q_g	$V_{DS} = 20\text{V}$, $V_{GS} = 10\text{V}$, $I_D = 8\text{A}$		30		nC
	Q_{gs}			5		nC
	Q_{gd}			7		nC
Diode Forward Voltage	V_{FSD}	$I_S = 8\text{A}$, $V_{GS} = 0\text{V}$			1.2	V

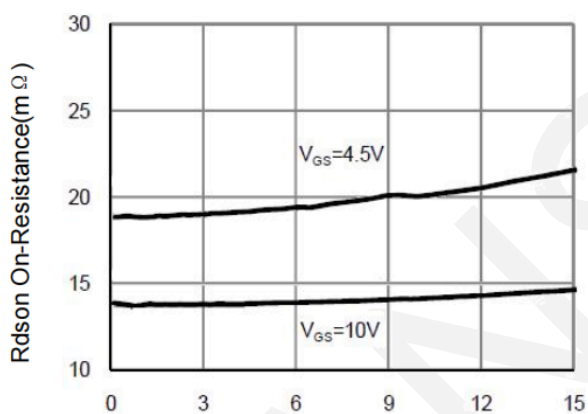
NMOS Typical electrical and thermal characteristics



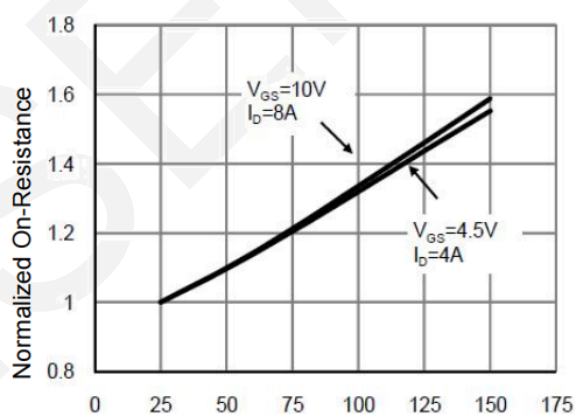
V_{DS} Drain-Source Voltage (V)
Output Characteristics



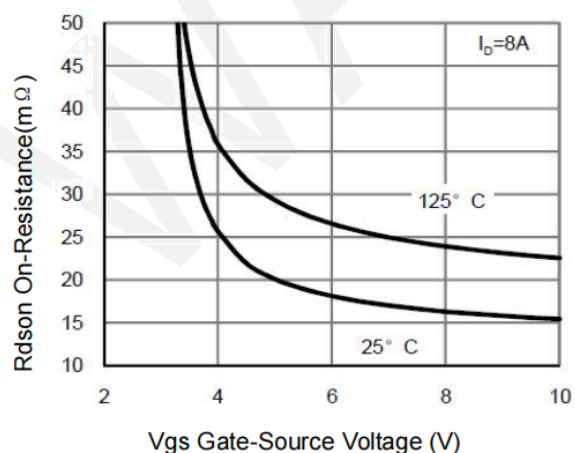
V_{GS} Gate-Source Voltage (V)
Transfer Characteristics



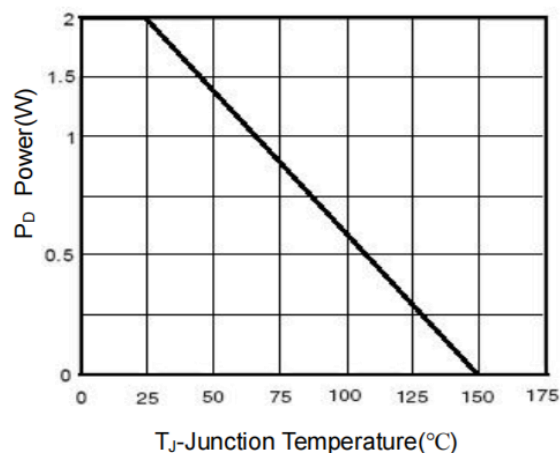
I_D - Drain Current (A)
Drain-Source On-Resistance



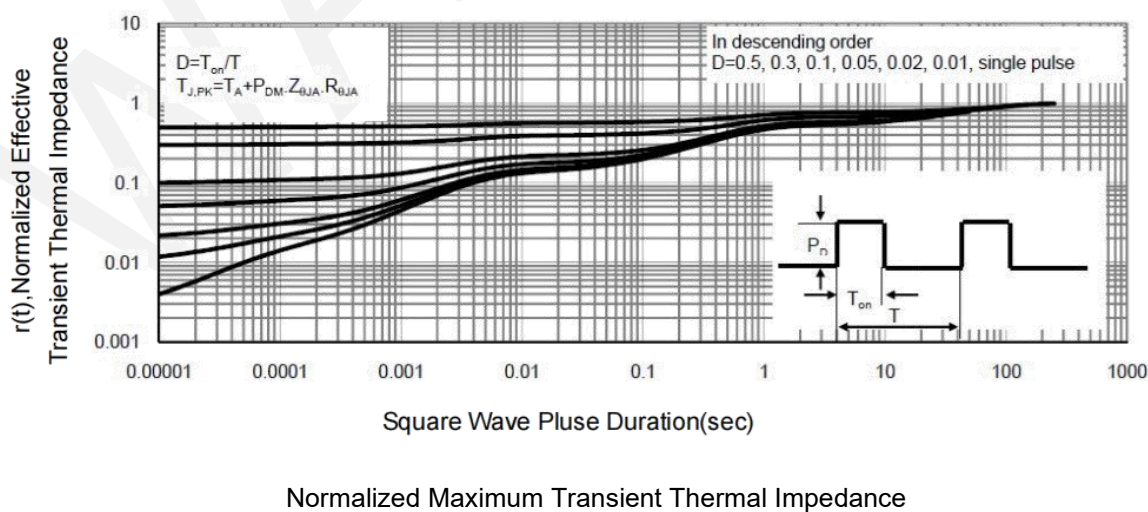
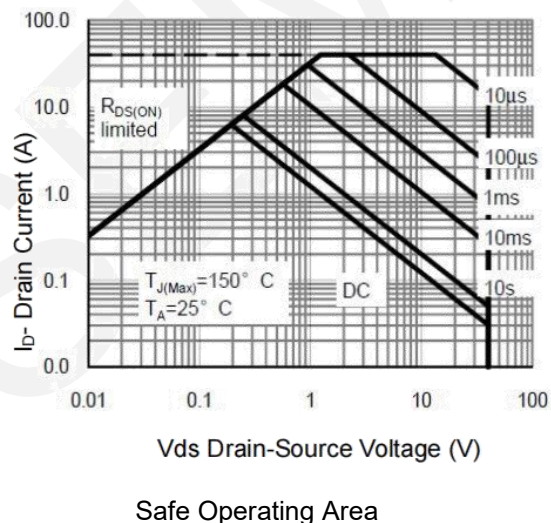
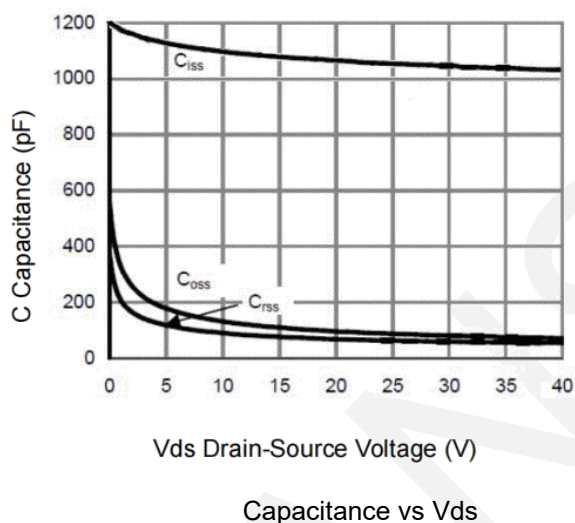
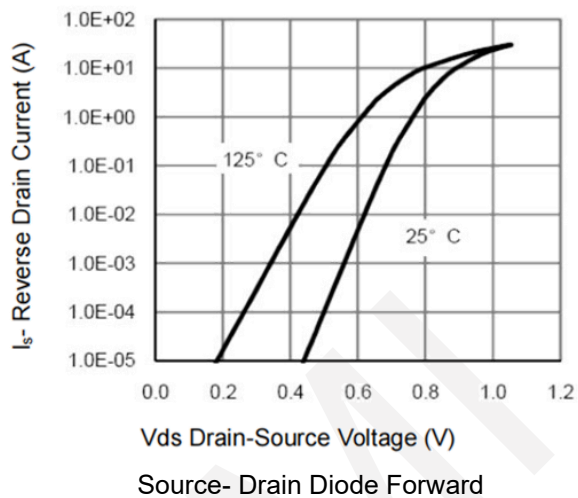
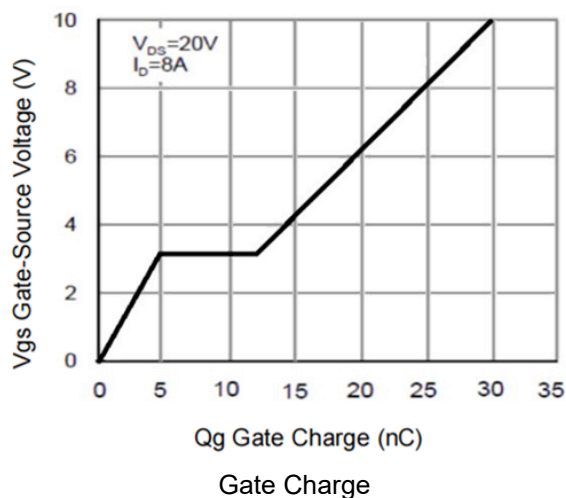
T_J -Junction Temperature(°C)
Drain-Source On-Resistance



$R_{DS(on)}$ vs V_{GS}



Power Dissipation

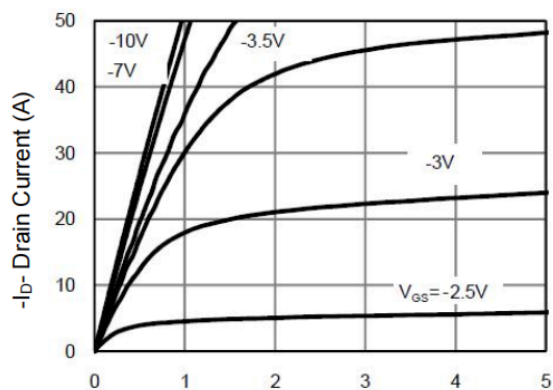


7. PMOS Electrical Characteristics at Ta=25°C

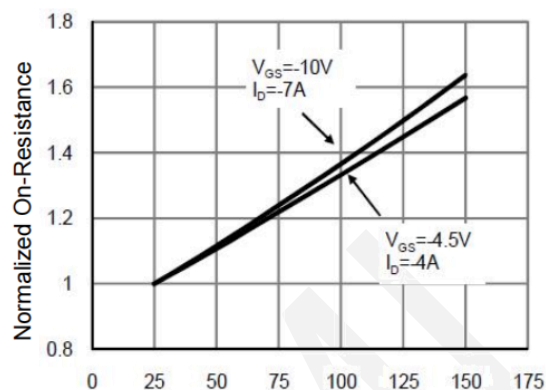
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$I_D = -250\mu A, V_{GS} = 0V$	-40			V
Zero-Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -40V, V_{GS} = 0V$			1	μA
Gate to Source Leakage Current	I_{GSS}	$V_{GS} = \pm 20V, V_{DS} = 0V$			± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_{DS}=-250\mu A$	-1.0	-1.5	-2.5	V
Static Drain to Source On-State Resistance	$R_{DS(on)}$	$I_D = -7A, V_{GS} = -10V$		33	49	m Ω
		$I_D = -4A, V_{GS} = -4.5V$		42	66	m Ω
Input Capacitance	C_{iss}	$V_{GS}=0V,$ $V_{DS}=-20V,$ Frequency=1.0MHz		1139	-	pF
Output Capacitance	C_{oss}			114	-	pF
Reverse Transfer Capacitance	C_{rss}			103	-	pF
Turn-ON Delay Time	$t_{d(on)}$	$V_{DD} = -20V$ $V_{GS} = -10V$ $R_{GEN}=6\Omega,$ $R_L=2.9\Omega,$		7.5	-	ns
Rise Time	t_r			5.5	-	ns
Turn-OFF Delay Time	$t_{d(off)}$			19	-	ns
Fall Time	t_f			7	-	ns
Total Gate Charge	Q_g	$V_{DS} = -20V,$ $V_{GS} = -10V,$ $I_D = -7A$		22.5		nC
	Q_{gs}			2.4		nC
	Q_{gd}			5.1		nC
Diode Forward Voltage	V_{FSD}	$I_S = -7A, V_{GS} = 0V$			-1.2	V

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

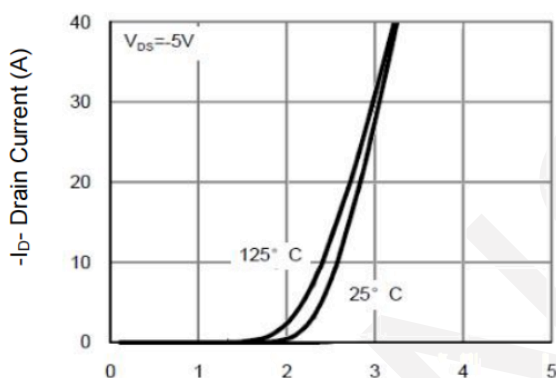
PMOS Typical electrical and thermal characteristics



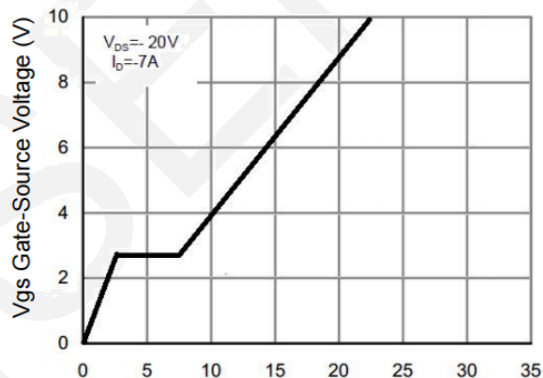
$-V_{DS}$ Drain-Source Voltage (V)
Output Characteristics



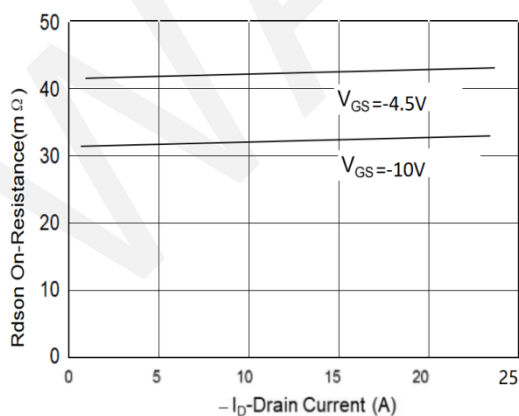
T_J -Junction Temperature ($^{\circ}C$)
 $R_{DS(on)}$ -Junction Temperature



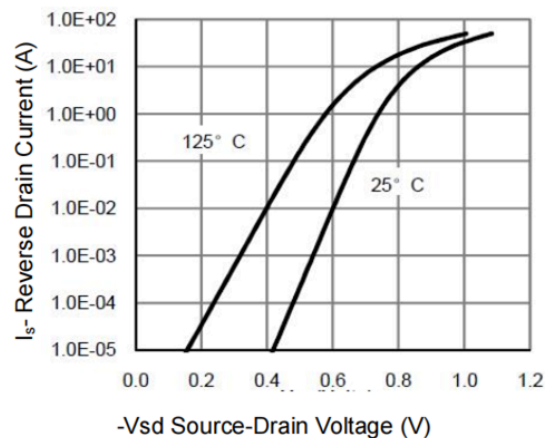
$-V_{GS}$ Gate-Source Voltage (V)
Transfer Characteristics



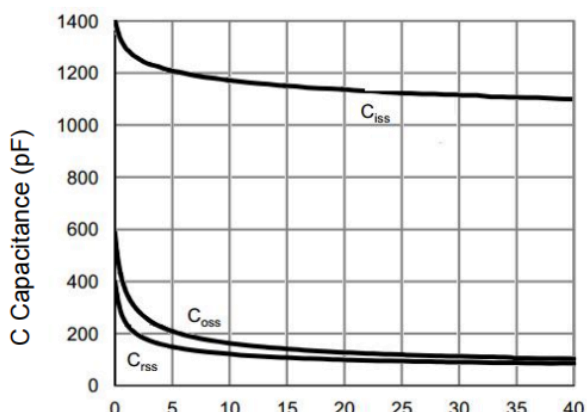
Q_G Gate Charge (nC)
Gate Charge



$R_{DS(on)}$ - Drain Current

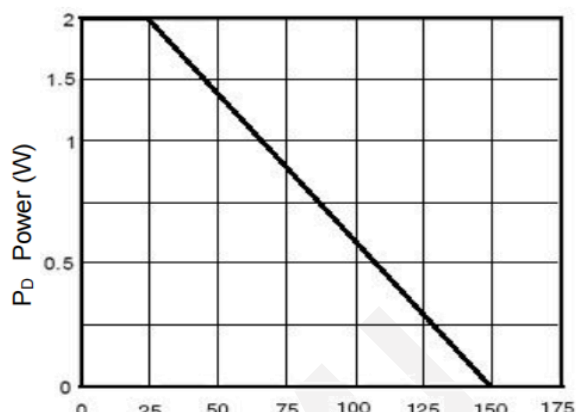


Source- Drain Diode Forward



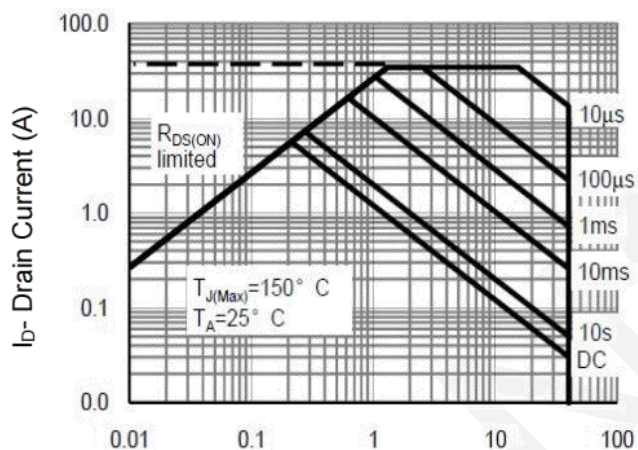
-Vds Drain-Source Voltage (V)

Capacitance vs Vds



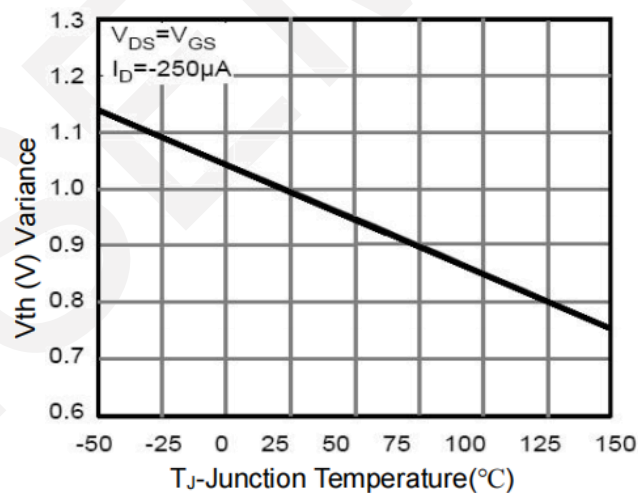
Tj-Junction Temperature(°C)

Power Dissipation

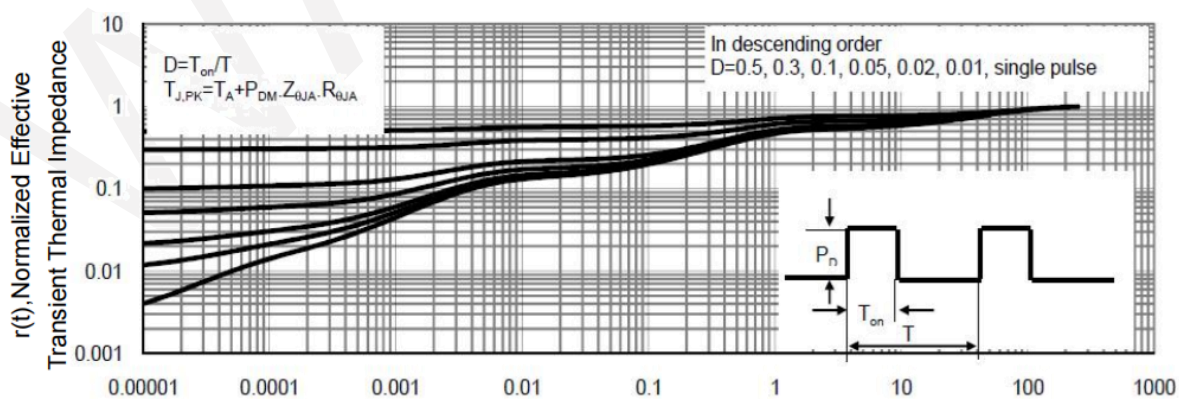


-Vds Drain-Source Voltage (V)

Safe Operation Area



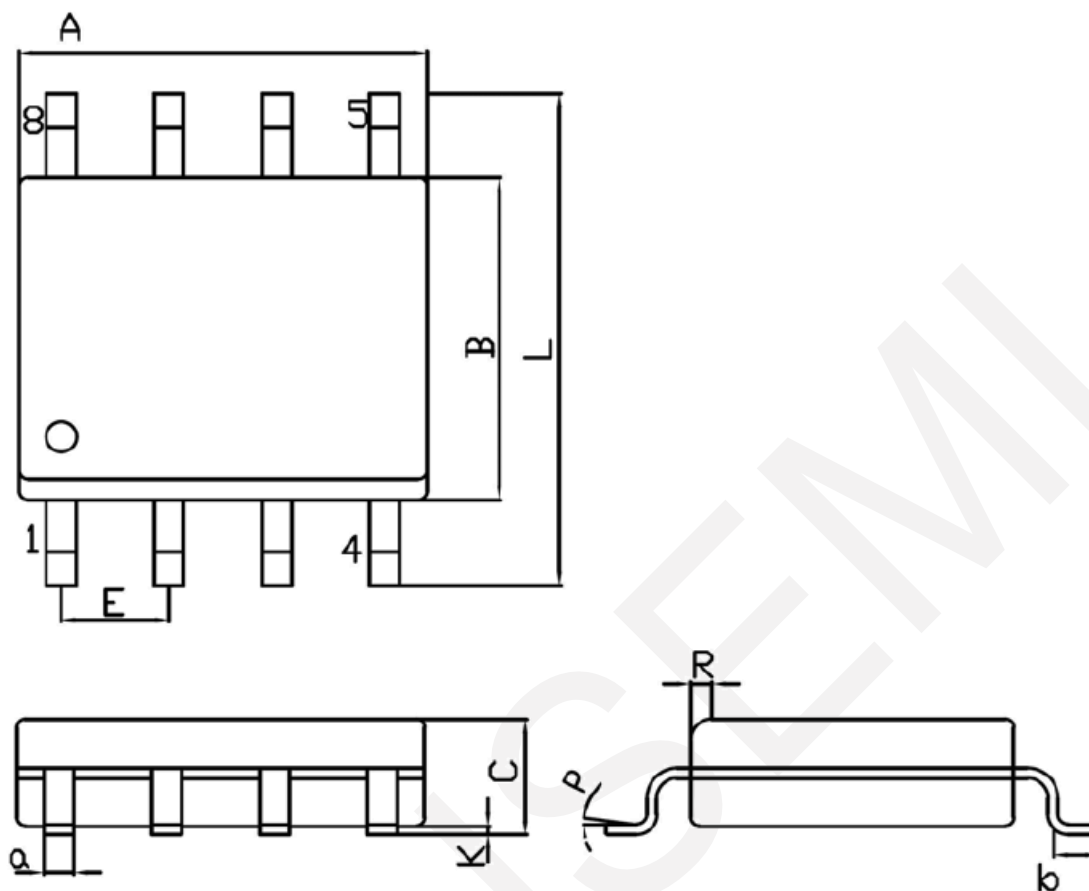
VGS(th) vs Junction Temperature



Square Wave Pulse Duration(sec)

Normalized Maximum Transient Thermal Impedance

8.Package Dimensions



Symbol	Dimensions In Millimeters		Symbol	Dimensions In Millimeters	
	Min	Max		Min	Max
A	4.70	5.10	C	1.35	1.75
B	3.70	4.10	a	0.35	0.49
L	5.80	6.20	R	0.30	0.60
E	1.27BSC		P	0°	7°
K	0.12	0.22	b	0.40	1.25

9. Important Notice

WAN SEMICONDUCTOR (NINGBO) CO.,LTD reserves the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services and to discontinue any product or service. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as “components”) are sold subject to WANSEMI’s terms and conditions of sale supplied at the time of order acknowledgment.

WANSEMI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in WANSEMI’s terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent WANSEMI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

WANSEMI assumes no liability for applications assistance or the design of Buyers’ products. Buyers are responsible for their products and applications using WANSEMI components. To minimize the risks associated with Buyers’ products and applications, Buyers should provide adequate design and operating safeguards.

No WANSEMI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Unless WANSEMI has specifically designated certain components which meet ISO/TS16949 requirements, mainly for automotive use, WANSEMI will not be responsible for any failure of such components to meet such requirements.